

SAND2011-5866C

Electrochemical Deposition of $\text{Bi}_2(\text{Te,Se})_3$ and $\text{Bi}_{1-x}\text{Sb}_x$ Nanowire Arrays on Silicon

21 July, 2011

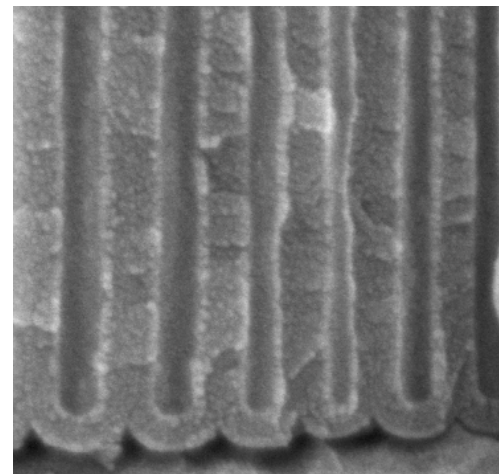
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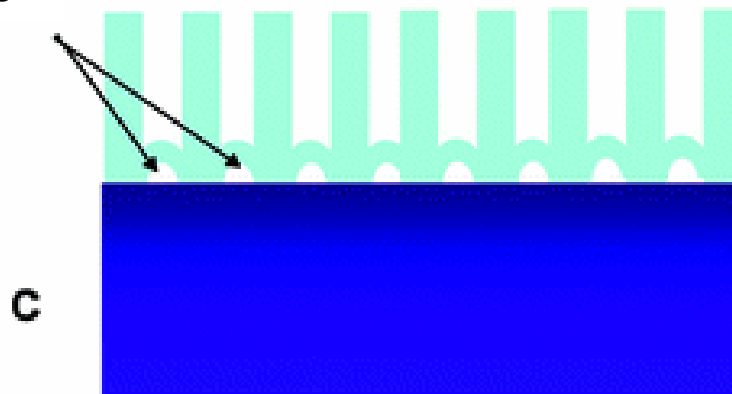
²Sandia National Laboratories, Livermore, CA.

Anodic aluminum oxide (AAO) templates on Si

- Pores in AAO tend to have a “test-tube” shape; open at one end with an oxide cap at the other end
- This barrier oxide interferes with electrodeposition
- Attempts to form AAO directly on a conductive substrate (Au, Si, ITO...) tend to have voids and delaminate



Voids

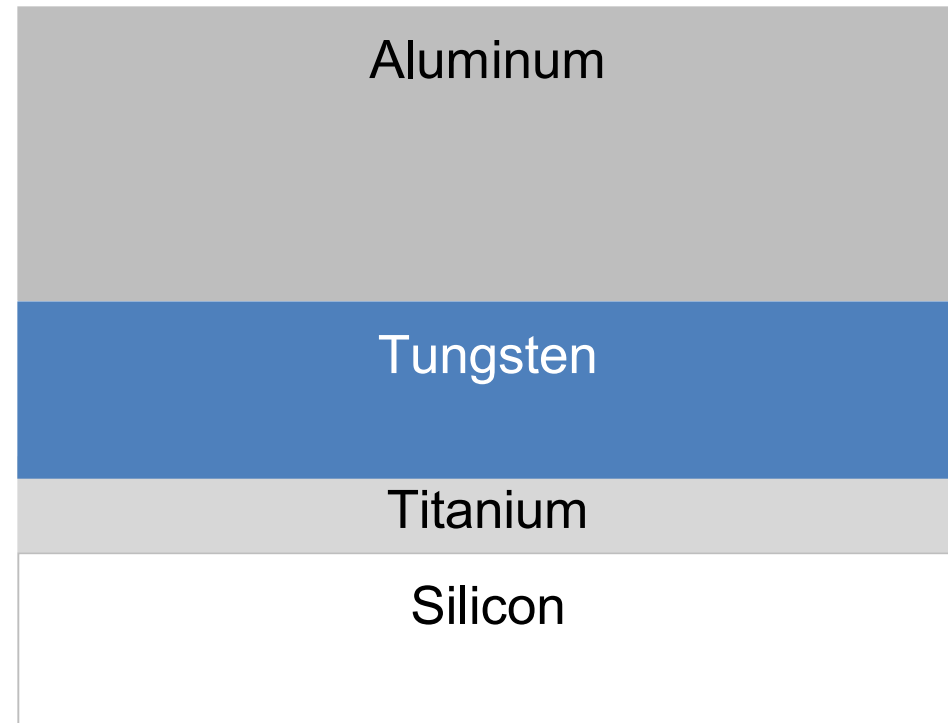


Foong, *ACS Nano* (2008).



AAO templates on Si

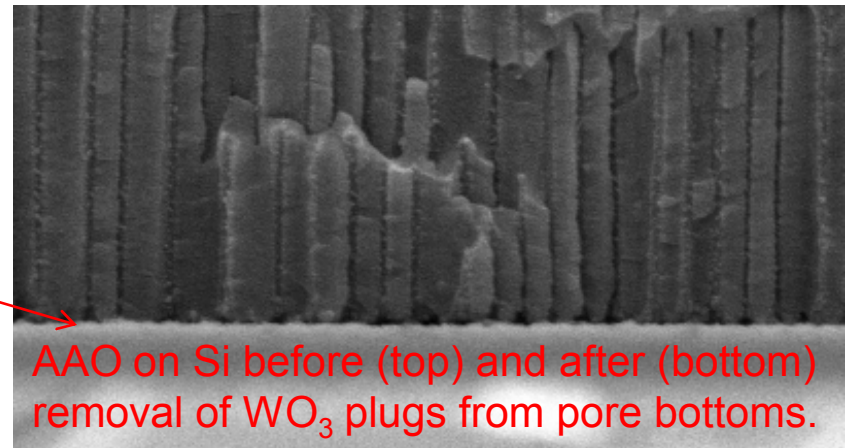
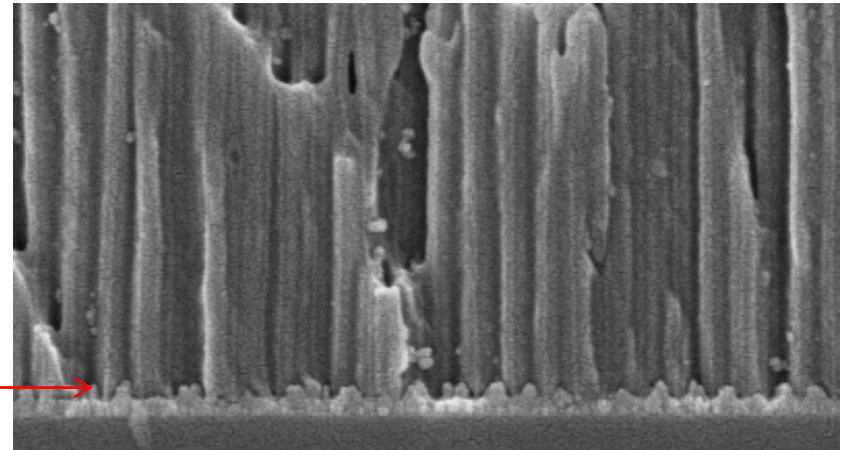
- Using a valve metal layer (e.g. W, Nb, Ta) under the Al alleviates this problem
 - WO_3 forms solid plugs at pore bottoms
 - WO_3 plugs can be selectively etched, leaving pores open at both ends



J. Oh, *Adv. Mater.* (2008)

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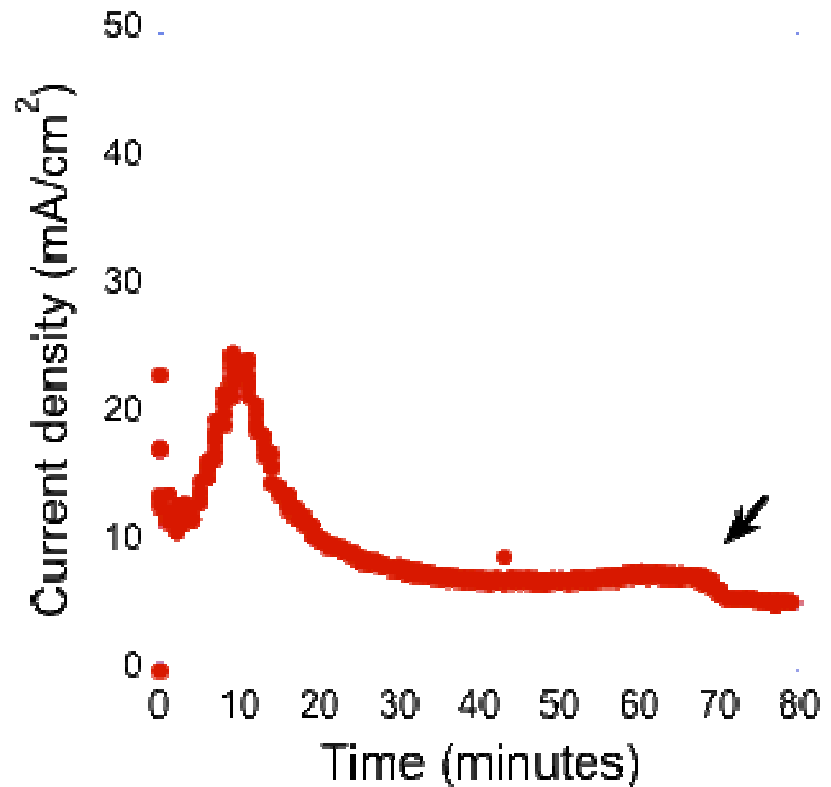


J. Oh, *Adv. Mater.* (2008)

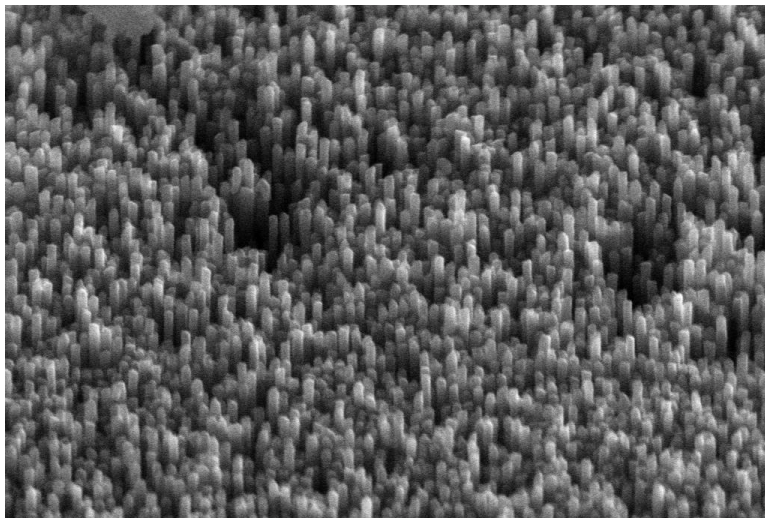
Forming AAO templates on Si

Target AAO dimensions:
75 nm pores
lengths up to $\sim 15\ \mu\text{m}$

- Anodize ($\sim 45\ \text{nm}$ pores)
 - 3 wt% oxalic acid, $1\ ^\circ\text{C}$, 40 V
 - $\sim 20\%$ dip in current signals that Al is converted to AAO
- Selective etch
 - pH 7 phosphate buffer
- Widening pores to $\sim 75\ \text{nm}$
 - 20 min $30\ ^\circ\text{C}$ 5 wt% H_3PO_4

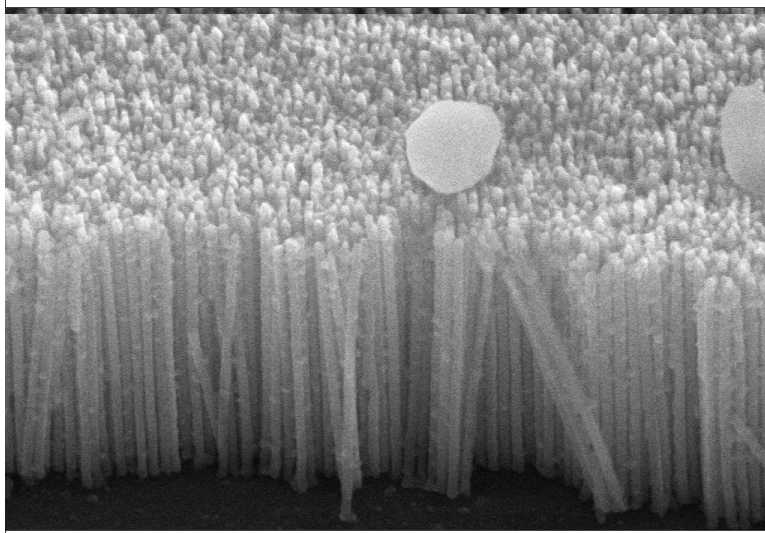


Electrodeposition of $\text{Bi}_2(\text{Te,Se})_3$ nanowire arrays



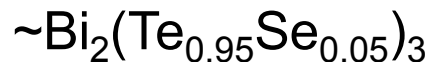
- Non-aqueous bath
 - 80 mM $\text{Bi}(\text{NO}_3)_3$, 40-80 mM TeCl_4 and 0.8-1.2 mM SeO_2 with 0.1 M KClO_4 in DMSO

- Pulsed electrochemical deposition
 - 1 s off, 20-500 ms on
 - On currents: 0.2-10 mA/cm^2



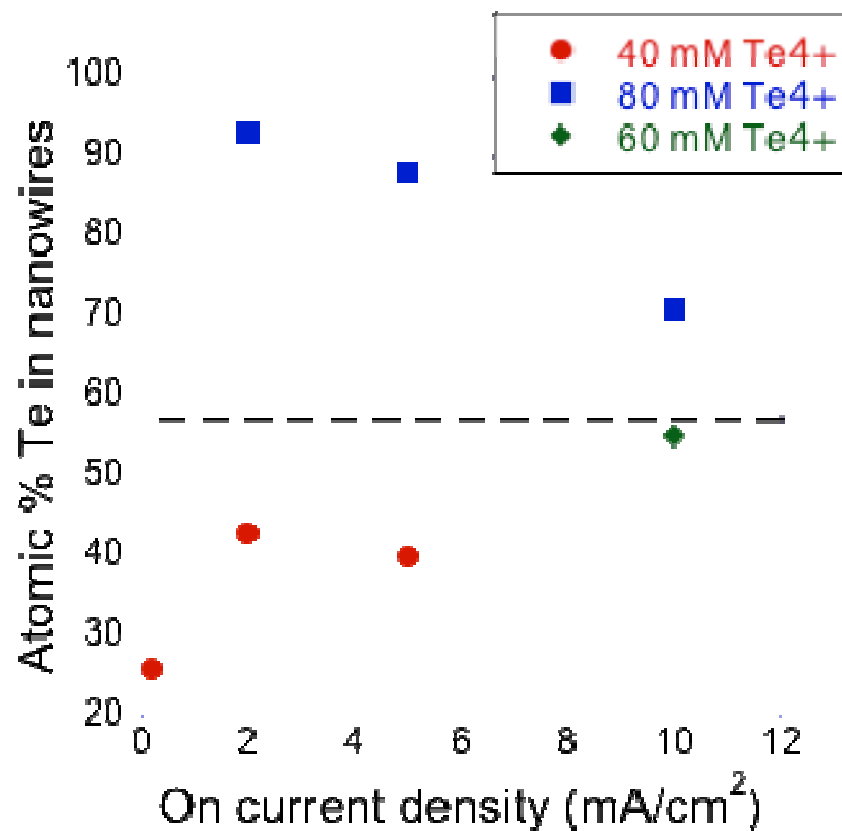
Electrodeposition of $\text{Bi}_2(\text{Te},\text{Se})_3$ nanowire arrays

Target composition (to start) :



40% Bi, 57% Te and 3% Se

- Plating parameters and bath composition must all be tuned to reach goal



$\text{Bi}_2(\text{Te,Se})_3$ nanowire arrays

Present iteration:

- 80 mM $\text{Bi}(\text{NO}_3)_3$, 60 mM TeCl_4 and 1.1 mM SeO_2
- 1 s off, 500 ms on at 10 mA/cm²

~75 nm diam, up to ~ 10 μm long

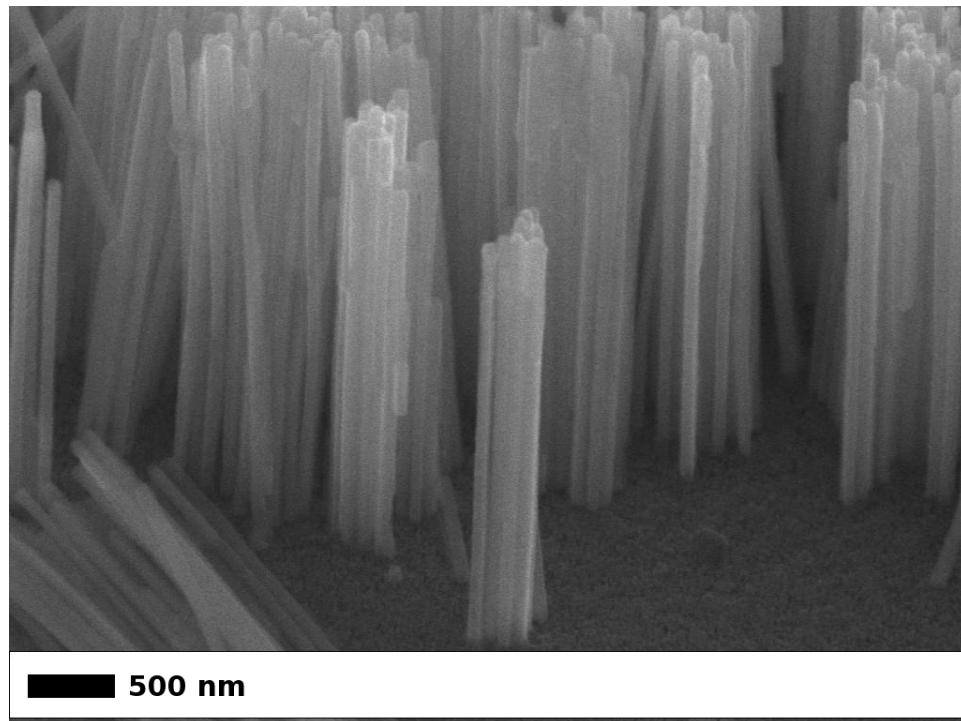
- Overall average composition (SEM EDS):

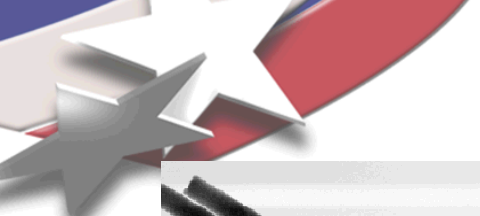
41.2 $\pm$ 1.1 at. % Bi

55.3 $\pm$ 1.0 at. % Te

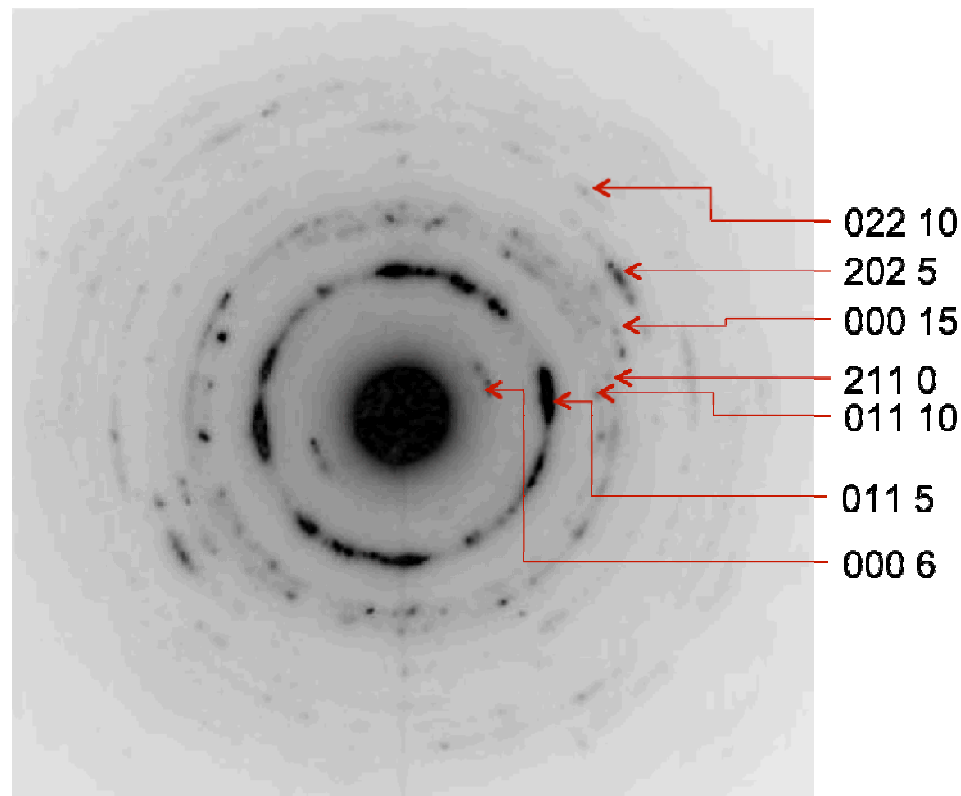
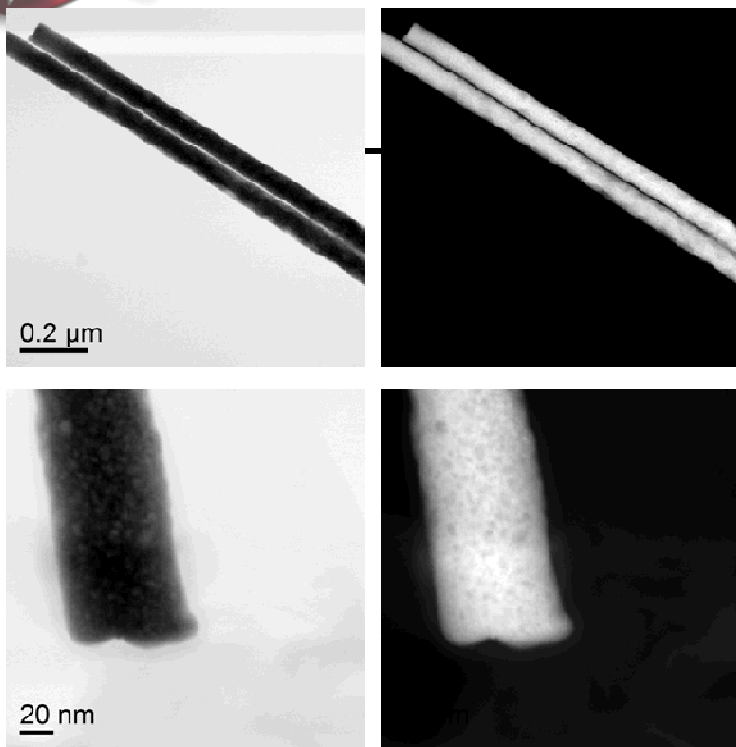
3.4 $\pm$ 0.04 at. % Se

- Optimal range
 - 40% Bi
 - 57-58.5% Te
 - 1.5-3% Se





$\text{Bi}_2(\text{Te,Se})_3$ nanowires



- Composition averaged over several nanowires (TEM EDS):

38.6 ± 2.8 at. % Bi

58.9 ± 4.3 at. % Te

2.5 ± 0.5 at. % Se

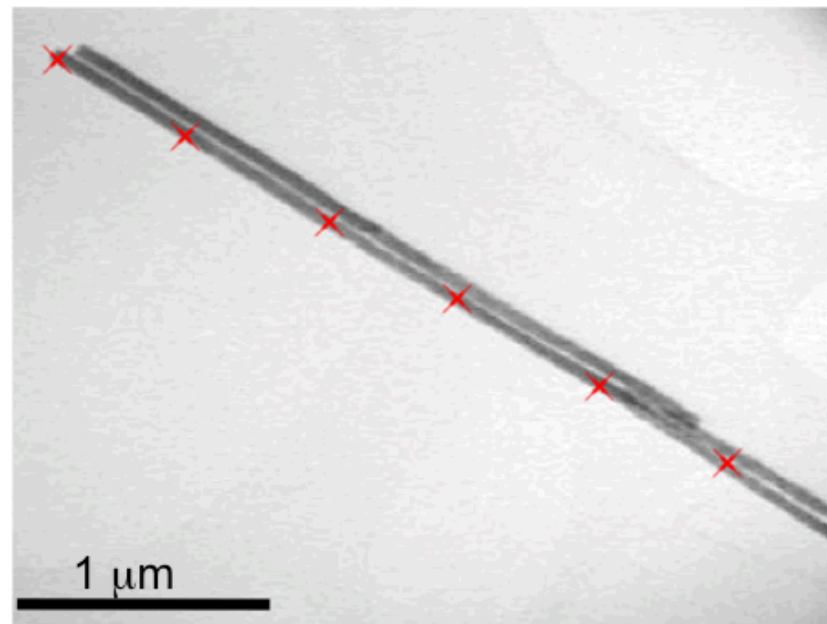
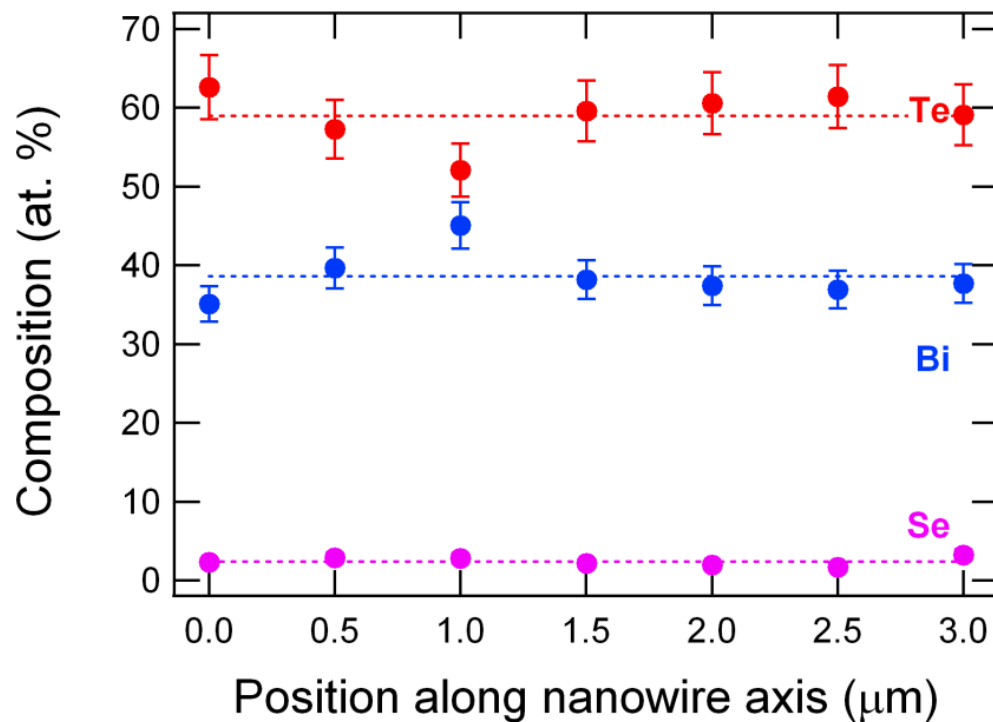
- Optimal range

40% Bi

57-58.5% Te

1.5-3% Se

$\text{Bi}_2(\text{Te,Se})_3$ nanowire composition is largely uniform along nanowire axis



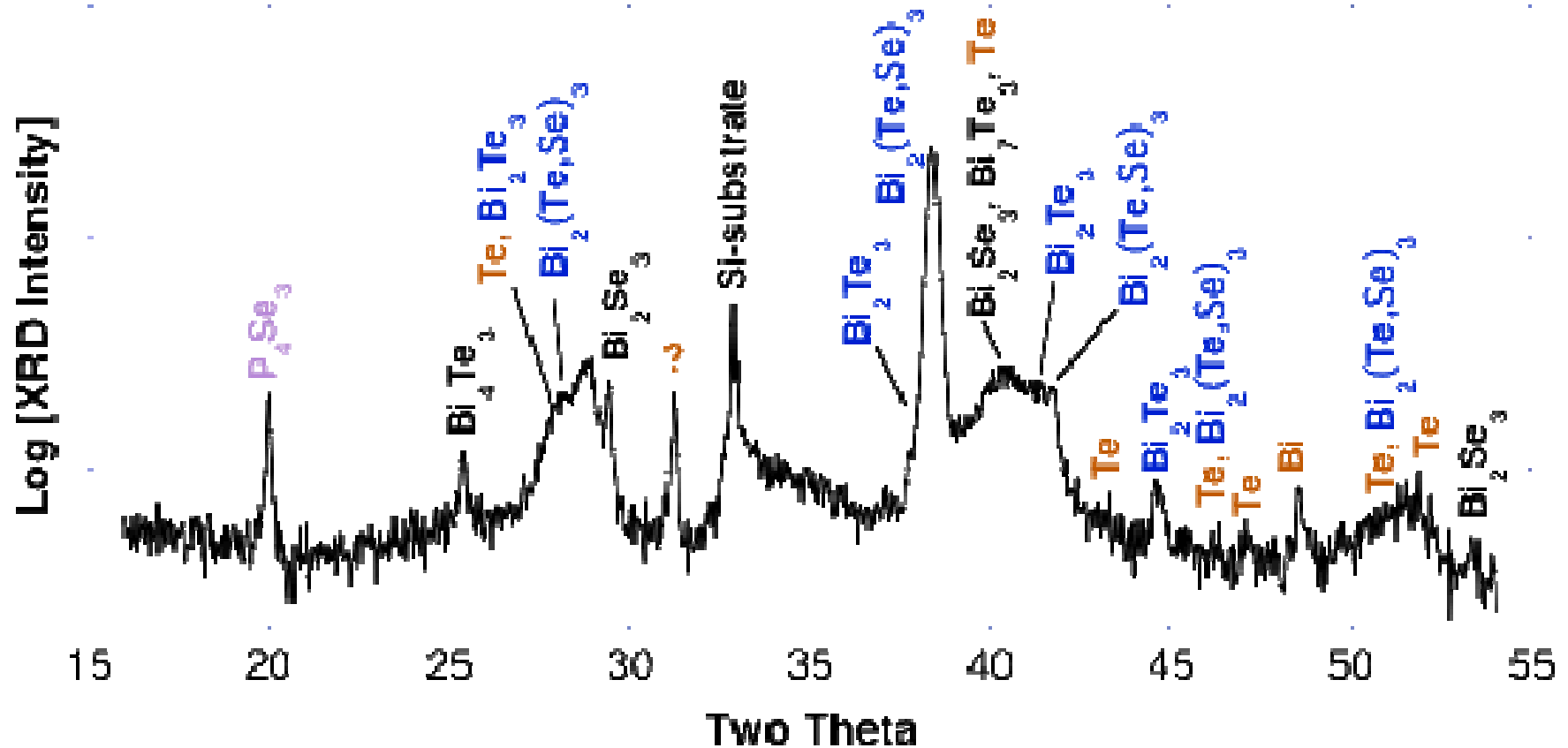


$\text{Bi}_2(\text{Te},\text{Se})_3$ nanowire arrays

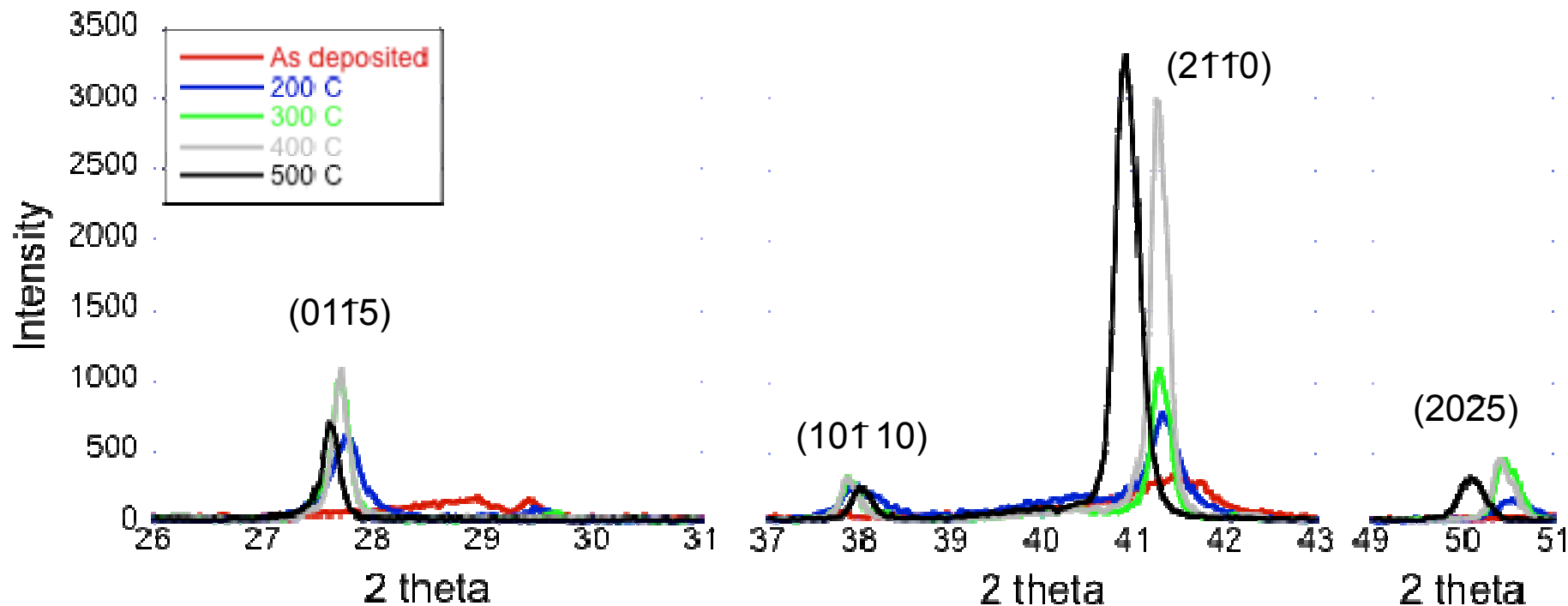
Composition	Reference
Optimal range $\text{Bi}_2\text{Te}_{2.925}\text{Se}_{0.075}$ – $\text{Bi}_2\text{Te}_{2.85}\text{Se}_{0.15}$	Xio, <i>Electrochim. Acta</i> (2008)
$\text{Bi}_{1.93}\text{Te}_{2.95}\text{Se}_{0.13}$	This work
$\text{Bi}_{2.1}\text{Te}_{2.4}\text{Se}_{0.5}$	Martín-González, <i>Nano Lett.</i> (2003)
$\text{Bi}_2\text{Te}_{2.3}\text{Se}_{0.7}$	Li, <i>Cryst. Growth Des.</i> (2008)
$\text{Bi}_2\text{Te}_{2.7}\text{Se}_{0.3}$	Li, <i>Superlattices Microstruct.</i> (2010)

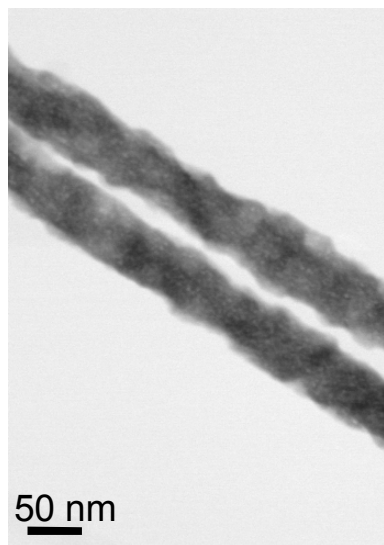
Closer to target composition than many reported $\text{Bi}_2(\text{Te},\text{Se})_3$ nanowires

Bi₂(Te,Se)₃ nanowire arrays

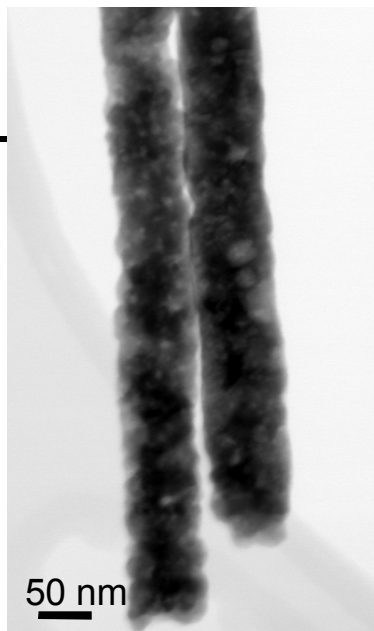


Annealing $\text{Bi}_2(\text{Te,Se})_3$ nanowire arrays (Mike Siegal W2.2)

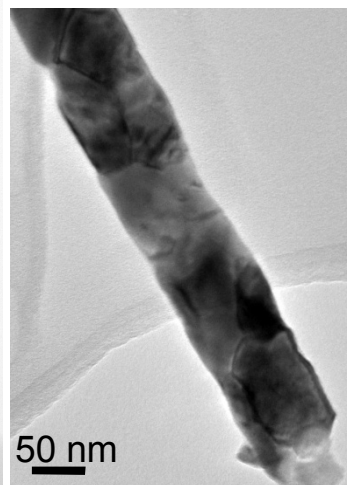




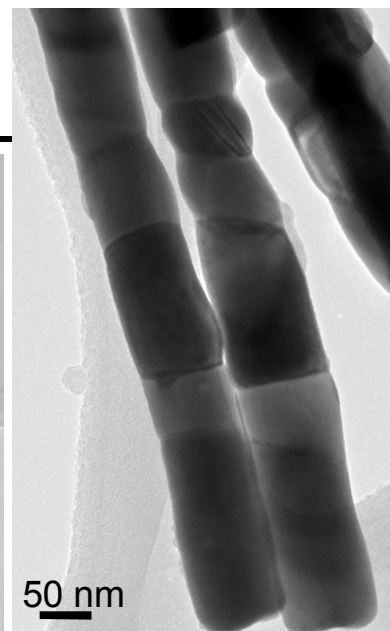
As Deposited



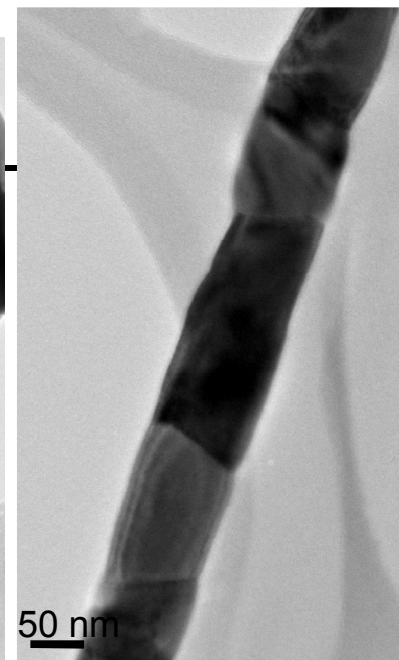
200°C



300°C



400°C



500°C

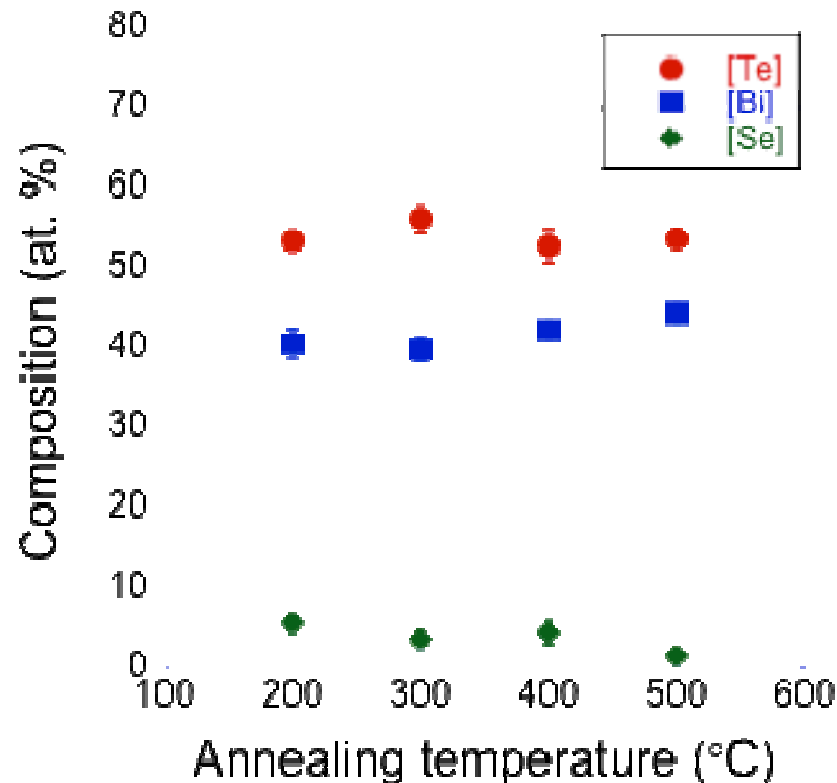
Grains < 10 nm most ~ 5 nm	Grains < 40 nm most ~ 20 nm	Grains up to 250 nm x full width Ave: 56 nm x 98 nm	Grains up to 320 nm x full width Ave: 74 nm x 145 nm	Grains up to 350 nm x full width
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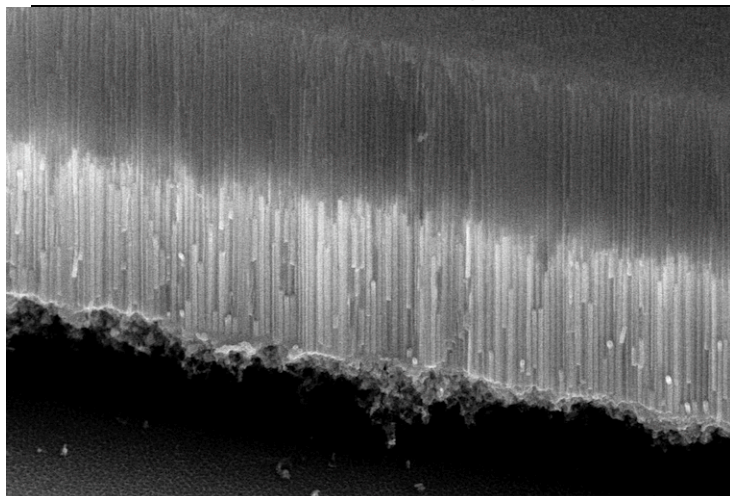
TEM images of $\text{Bi}_2(\text{Te}_{1-x}\text{Se}_x)_3$ nanowires annealed for 30 minutes in 3 % H_2/Ar

Annealing $\text{Bi}_2(\text{Te,Se})_3$ nanowire arrays

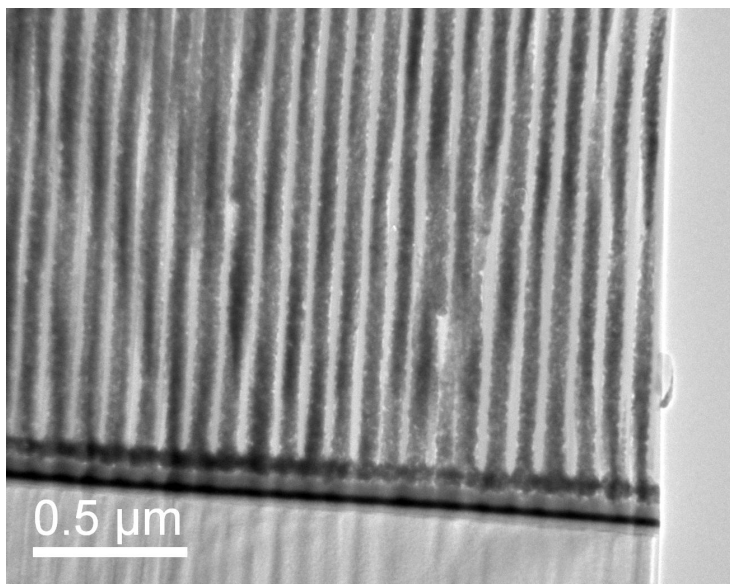
Temp (°C)	Phases (from XRD)
As deposited	Bi_2Te_3 type Bismuth-rich phases (Bi_4Te_3 , Bi_7Te_3 types) Elemental Bi and Te
90	Bi_2Te_3 type
200	Bi_2Te_3 type
300	Bi_2Te_3 type
400	Bi_2Te_3 type
500	Bi_2Te_3 type, Bi_4Te_5 type



Electrodeposition of $\text{Bi}_{1-x}\text{Sb}_x$ nanowire arrays (Graham Yelton, Poster 17)



1 μm



0.5 μm

- Bath: 30-50 mM $\text{Bi}(\text{NO}_3)_3$, and 30-50 mM SbI_3 with 0.1 M KClO_4 in DMSO
- Galvanostatic Pulse Strike (10 cycles):
 - T off = 1.0 s, I off = -0.2 mA/cm²
 - T on = 0.2 s, I on = -30-40 mA/cm²
- Galvanostatic Pulse plating:
 - T off = 1.5 s, I off = -0.2 mA/cm²
 - T on = 0.5 s, I on = -1-3 mA/cm²



Acknowledgments

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